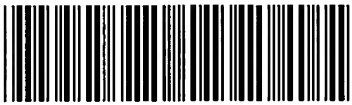


**Search Notes**

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Examiner

Anne M. Hines

Applicant(s)/Patent under  
Reexamination

HAN, IN-TAEK

Art Unit

2879

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous search	1/24/2006	<i>Ant</i>

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
searched East; see search history	1/24/2006	<i>Ant</i>